

SUPPLEMENTARY MATERIAL

A New Approach for Glyco-Functionalization of Collagen-Based Biomaterials

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1. AFM analysis

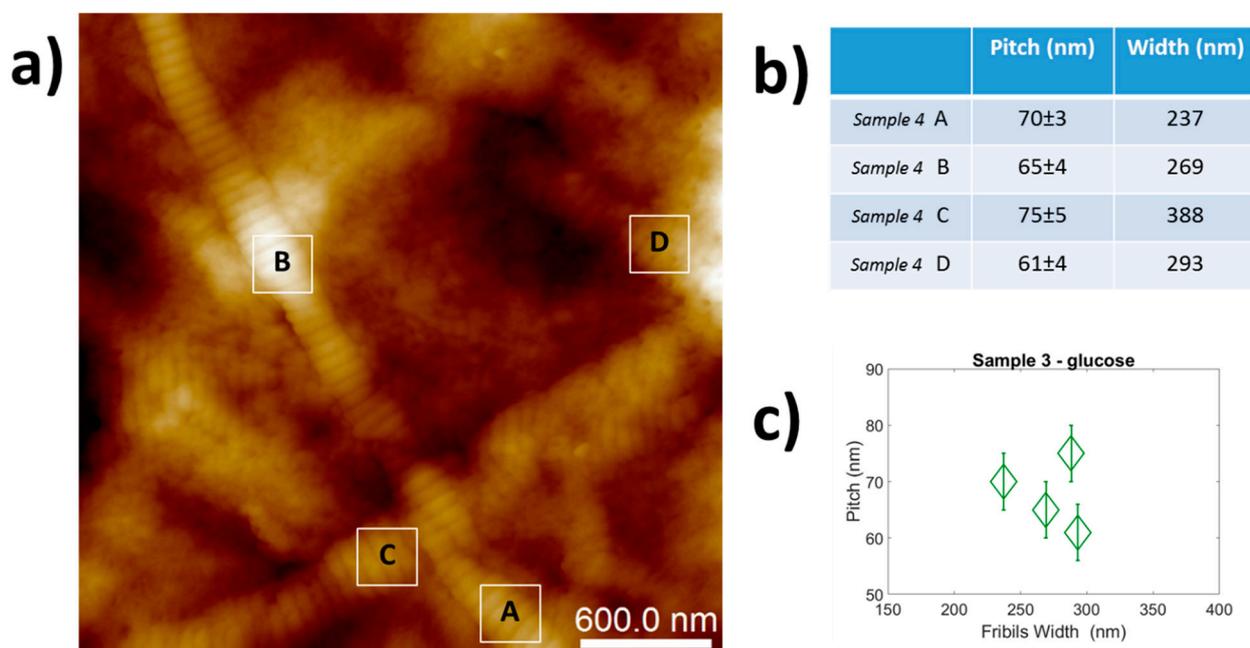


Figure Supplementary 1: a) 3x3 μm^2 AFM topography image of Sample 3 (Glc) reported in the main text (Figure 4) with the indication of the chosen fibrils for the pitch analysis, b) the pitch and the width of each fibrils and c) the absence of correlation of the pitch with the fibril's width

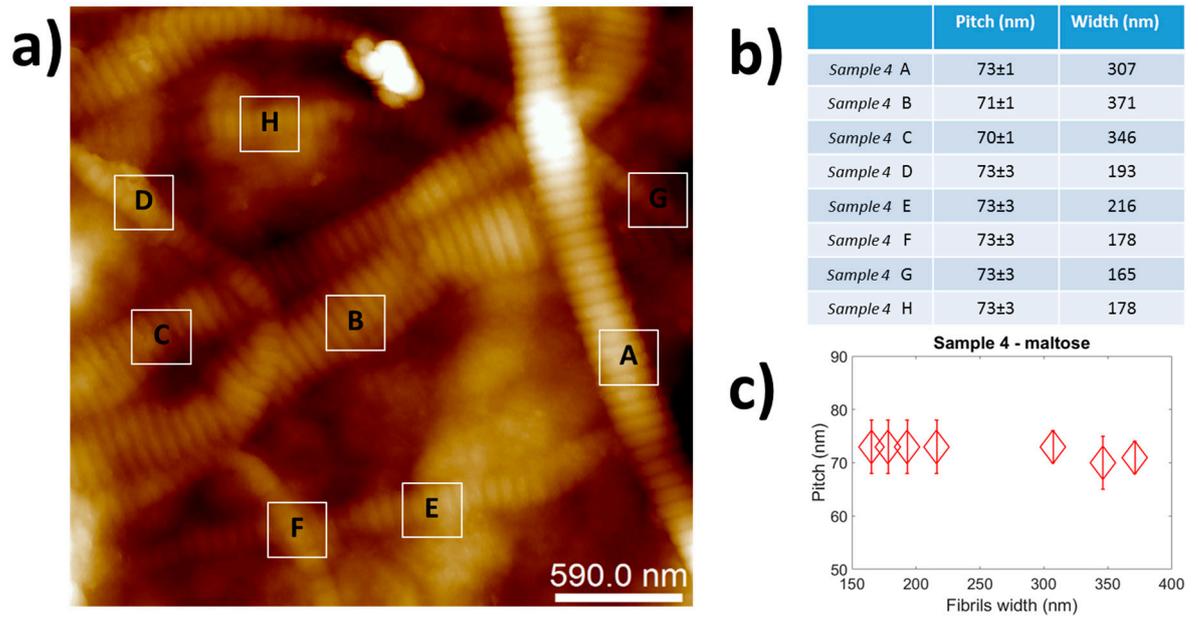


Figure Supplementary 2. a) 3x3 μm^2 AFM topography image of Sample 4 (Malt) reported in the main text (Figure 4) with the indication of the chosen fibrils for the pitch analysis, b) the pitch and the width of each fibrils and c) the absence of correlation of the pitch with the fibril's width.

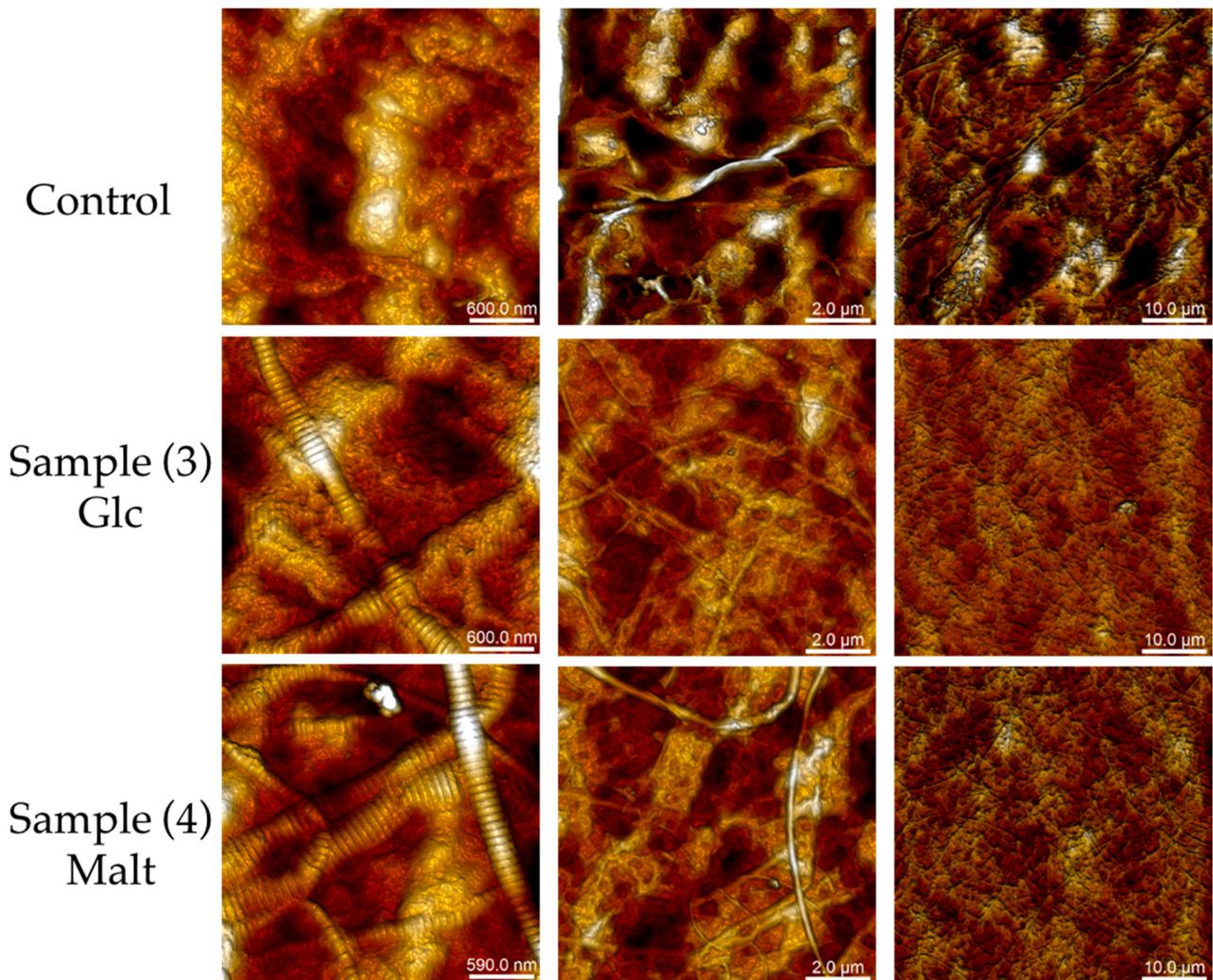
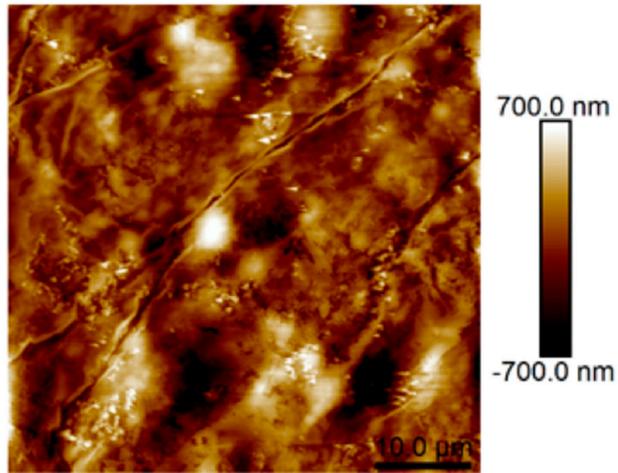
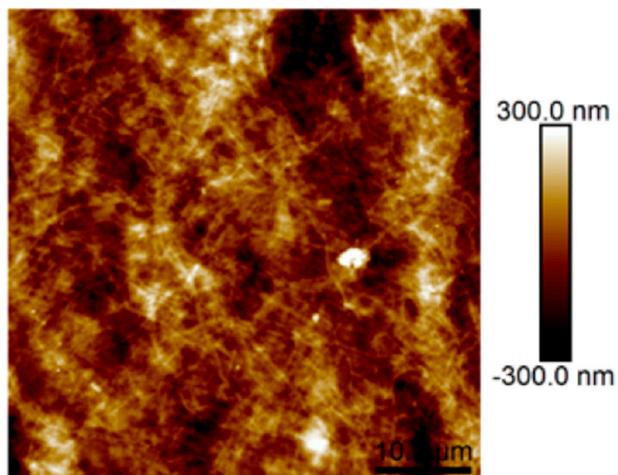


Figure Supplementary 3. 3D Lighting (Nanoscope Analysis software -Bruker Corporation, Santa Barbara, CA) image of collagen matrices acquired in PeakForce mode in air reported in the Figure 4. Different scan sized images of collagen films without further modification (line 1), glucose (line 2) and maltose (line 3) neoglycosylated collagen films were collected. From left to right: column 1 ($3 \times 3 \mu\text{m}^2$, 512×512 pixel, Z-scale 200nm), column 2 ($10 \times 10 \mu\text{m}^2$, 512×512 pixel, Z-scale 500nm), column 3 ($50 \times 50 \mu\text{m}^2$, 512×512 pixel, Z-scale 1.4 μm).

Control



Sample (3)
Glc



Sample (4)
Malt

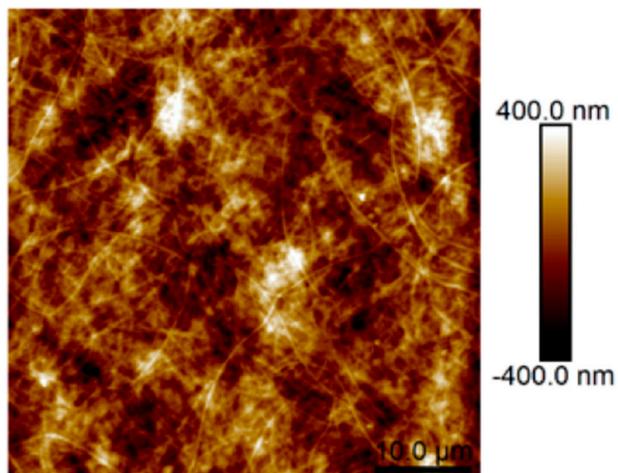


Figure Supplementary 4:

50x50 μm² AFM topography image of collagen films reported in the main text (Figure 4) with variable z-range, from top to bottom: no-functionalized films, glucose and maltose neoglycosylated collagen films.

2. AFM Surface Roughness

The roughness of the samples was calculated in accordance with the standard formula $R_q = \sqrt{\frac{\sum Z_i^2}{N}}$ by using the available tool of the commercial Nanoscope Analysis software (Bruker Corporation, Santa Barbara, CA). The images were splitted into 25 different regions and the resulting surface roughness are evaluated and averaged (values reported in the main text are mean value \pm st.dev).

Also the Ra for each sample was evaluated by the means of the standard formula $R_a = \frac{1}{N} \sum_{j=1}^N |Z_j|$ reporting values showing the same behavior than the ones found for the Rq (Ra = 165 \pm 36 nm for CT, Ra = 59 \pm 12 nm for Sample 3 and Ra = 88 \pm 18 nm for Sample 4).